

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application

Applicant(s): Michael J. Berman
Serial No.: 09/553,140
Confirm. No.: 4444
Filing Date: April 20, 2000
Art Unit: 2624
Examiner: Aaron W. Carter

Title: Determination of Film Thickness During Chemical Mechanical Polishing

AMENDMENT AND RESPONSE TO OFFICE ACTION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the outstanding non-final Office Action dated October 16, 2009, Applicant respectfully requests reconsideration of the above-identified application in view of the amendments and remarks herein.